

SiC JFET Division

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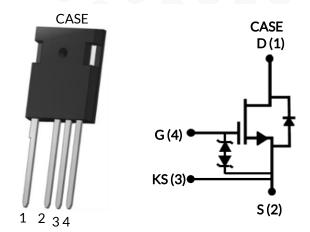








UF4SC120030K4S



Part Number	Part Number Package	
UF4SC120030K4S	TO-247-4L	UF4SC120030K4S







Silicon Carbide (SiC) Cascode JFET -EliteSiC, Power N-Channel, TO-247-4L, 1200 V, 30 mohm

Rev. B, January 2025

Description

The UF4SC120030K4S is a 1200V, $30m\Omega$ G4 SiC FET. It is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's standard gate-drive characteristics allows for a true "drop-in replacement" to Si IGBTs, Si FETs, SiC MOSFETs or Si superjunction devices. Available in the TO-247-4L package, this device exhibits ultra-low gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads and any application requiring standard gate drive.

Features

- On-resistance R_{DS(on)}: 30mΩ (typ)
- Operating temperature: 175°C (max)
- Excellent reverse recovery: Q_{rr} = 277nC
- Low body diode V_{FSD}: 1.22V
- ◆ Low gate charge: Q_G = 37.8nC
- Threshold voltage V_{G(th)}: 4.8V (typ) allowing 0 to 15V drive
- Low intrinsic capacitance
- ESD protected: HBM class 2 and CDM class C3
- TO-247-4L package for faster switching, clean gate waveforms

Typical applications

- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating













Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		1200	V
Cata assuras valtass	\/	DC	-20 to +20	V
Gate-source voltage	V_{GS}	AC (f > 1Hz)	-25 to +25	V
Continuous drain current ¹	1	T _C ≤ 40°C	53	Α
Continuous drain current	I _D	T _C =100°C	41	А
Pulsed drain current ²	I _{DM}	T _C = 25°C	164	А
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =3.6A	97	mJ
SiC FET dv/dt ruggedness	dv/dt	V _{DS} ≤ 800V	200	V/ns
Power dissipation	P _{tot}	T _C = 25°C	341	W
Maximum junction temperature	$T_{J,max}$		175	°C
Operating and storage temperature	T_J,T_STG		-55 to 175	°C
Max. lead temperature for soldering, 1/8" from case for 5 seconds	T _L		250	°C

- 1. Limited by bondwires
- 2. Pulse width t_p limited by $T_{J,max}$
- 3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Doromotor	Symbol	Test Conditions	Conditions			Units
Parameter	Зуппон	rest Conditions	Min	Тур	Max	Units
Thermal resistance, junction-to-case	$R_{ heta$ JC			0.34	0.44	°C/W













Electrical Characteristics (T_J = +25°C unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions		Units		
- arameter			Min	Тур	Max	Offics
Drain-source breakdown voltage	BV _{DS}	V_{GS} =0V, I_D =1mA	1200			V
		V _{DS} =1200V,		1	50	
Total drain leakage current	lass	$V_{GS}=0V, T_J=25$ °C				^
Total di alli leakage cull elit	I _{DSS}	V _{DS} =1200V,		15		- μΑ
		$V_{GS}=0V, T_J=175$ °C		15		
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _J =25°C,		6	20	μА
		V _{GS} =-20V / +20V				
	R _{DS(on)}	V_{GS} =12V, I_{D} =20A,		30	39	
		T _J =25°C				
Drain-source on-resistance		$V_{GS}=12V, I_{D}=20A,$		56		mΩ
Drain source on resistance		T _J =125°C				11122
		V_{GS} =12V, I_{D} =20A,		77		
		T _J =175°C				
Gate threshold voltage	$V_{G(th)}$	V_{DS} =5V, I_{D} =10mA	4	4.8	6	V
Gate resistance	R_{G}	f=1MHz, open drain		4.5		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions		Units		
			Min	Тур	Max	UTILS
Diode continuous forward current ¹	I _S	T _C ≤ 40°C			53	Α
Diode pulse current ²	I _{S,pulse}	T _C = 25°C			164	А
Forward voltage	V _{FSD}	V _{GS} =0V, I _S =15A, T _J =25°C		1.22	1.35	V
		V _{GS} =0V, I _S =15A, T _J =175°C		1.68		- v
Reverse recovery charge	Q _{rr}	V_R =800V, I_S =30A, V_{GS} =0V, R_G =18 Ω		277		nC
Reverse recovery time	t _{rr}	di/dt=1840A/μs, T _J =25°C		14		ns
Reverse recovery charge	Q _{rr}	V_R =800V, I_S =30A, V_{GS} =0V, R_G =18 Ω		298		nC
Reverse recovery time	t _{rr}	di/dt=1840A/μs, Τ _J =150°C		12.8		ns













Typical Performance - Dynamic

Damanatan	Symbol Test Conditions	Took Comditions	Value			11.20
Parameter		lest Conditions -	Min	Тур	Max	- Units
Input capacitance	C_{iss}	- V _{DS} =800V, V _{GS} =0V - f=100kHz		1450		
Output capacitance	C_{oss}			65		pF
Reverse transfer capacitance	C_{rss}			2		
Effective output capacitance, energy related	C _{oss(er)}	V _{DS} =0V to 800V, V _{GS} =0V		82		pF
Effective output capacitance, time related	C _{oss(tr)}	V _{DS} =0V to 800V, V _{GS} =0V		150		pF
C _{OSS} stored energy	E _{oss}	V _{DS} =800V, V _{GS} =0V		26		μЈ
Total gate charge	Q_{G}	V _{DS} =800V, I _D =30A, V _{GS} = 0V to 15V		37.8		
Gate-drain charge	Q_{GD}			8		nC
Gate-source charge	Q_{GS}			11.8		
Turn-on delay time	$t_{d(on)}$	Note 4 and 5, V _{DS} =800V, I _D =30A, Gate		12		- ns
Rise time	t_r			19		
Turn-off delay time	t _{d(off)}			77		
Fall time	t _f	Driver =0V to +15V, $R_{G ON} = 1\Omega$, $R_{G OFF} = 18\Omega$,		11		
Turn-on energy including R _S energy	E _{ON}	inductive Load, FWD: same device with V_{GS} = 0V and R_G = 18 Ω , Snubber: R_s =10 Ω , C_s =47pF		423		μ
Turn-off energy including R _S energy	E _{OFF}			73		
Total switching energy	E _{TOTAL}			496		
Snubber R _S energy during turn-on	E _{RS_ON}	T _J =25°C		1.7		
Snubber R _S energy during turn-off	E _{RS_OFF}			1.5		
Turn-on delay time	t _{d(on)}			13		
Rise time	t _r	Note 4 and 5,		20		ns
Turn-off delay time	t _{d(off)}	V _{DS} =800V, I _D =30A, Gate		85		
Fall time	t _f	Driver =0V to +15V, $R_{G ON}=1\Omega, R_{G OFF}=18\Omega,$		12		
Turn-on energy including R _S energy	E _{ON}	inductive Load, FWD: same device with V_{GS} = $0V$ and $R_G = 18\Omega$, Snubber: $R_s = 10\Omega$, $C_s = 47pF$ $T_J = 150^{\circ}C$		500		
Turn-off energy including R _S energy	E _{OFF}			97		
Total switching energy	E _{TOTAL}			597		μJ
Snubber R _S energy during turn-on	E _{RS_ON}			1.6		
Snubber R _S energy during turn-off	E _{RS_OFF}			1.4		

^{4.} Measured with the switching test circuit in Figure 26.

^{5.} In this datasheet, all the switching energies (turn-on energy, turn-off energy and total energy) presented in the tables and Figures include the device RC snubber energy losses.





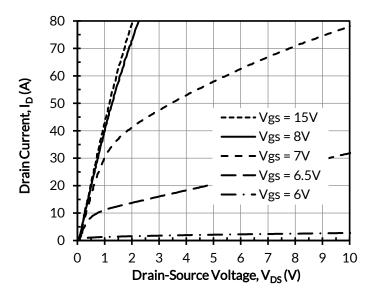








Typical Performance Diagrams



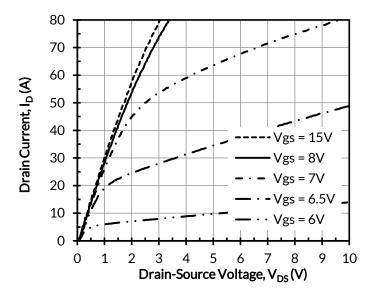
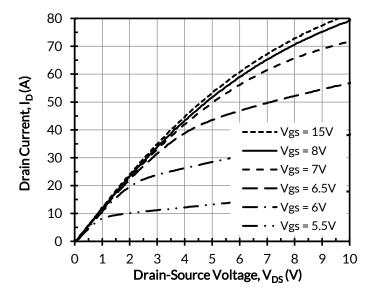


Figure 1. Typical output characteristics at $T_J = -55$ °C, tp < 250µs

Figure 2. Typical output characteristics at T_J = 25°C, tp < 250 μ s



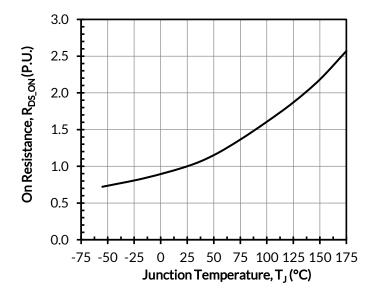


Figure 3. Typical output characteristics at T_J = 175°C, tp < 250 μ s

Figure 4. Normalized on-resistance vs. temperature at $V_{GS} = 12V$ at $I_D = 30A$





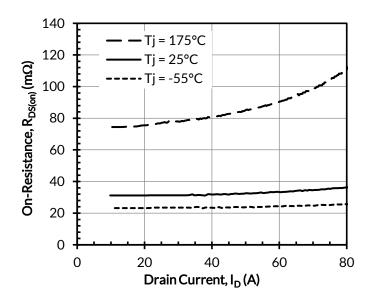












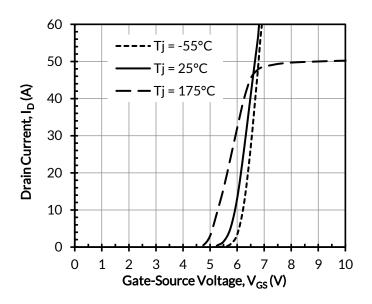
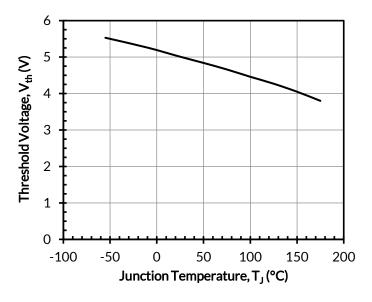


Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

Figure 6. Typical transfer characteristics at $V_{DS} = 5V$



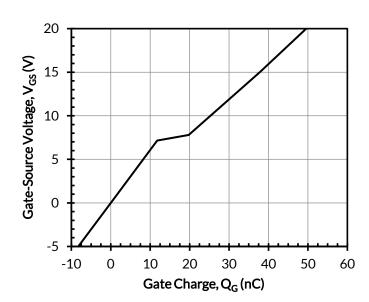


Figure 7. Threshold voltage vs. junction temperature at Figure 8. Typical gate charge at V_{DS} = 5V and I_D = 30A V_{DS} = 5V and I_{D} = 10mA













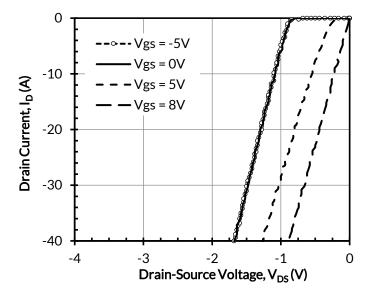
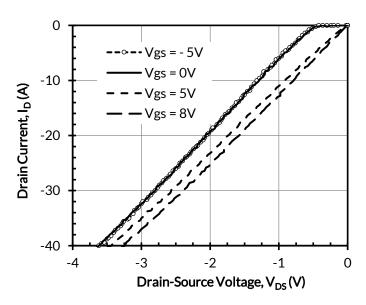


Figure 9. 3rd quadrant characteristics at T_J = -55°C

Figure 10. 3rd quadrant characteristics at $T_J = 25$ °C



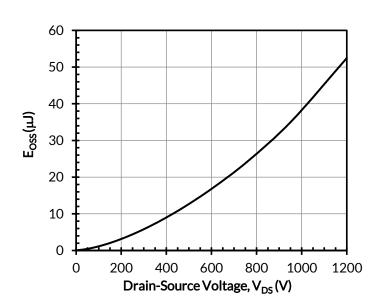


Figure 11. 3rd quadrant characteristics at T_J = 175°C

Figure 12. Typical stored energy in C_{OSS} at $V_{GS} = 0V$



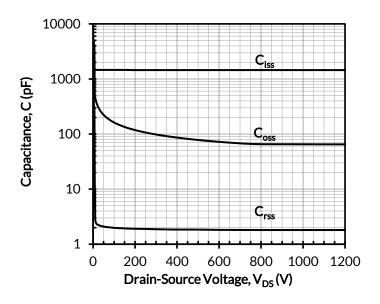












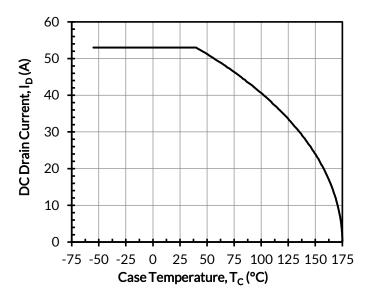


Figure 13. Typical capacitances at f = 100kHz and V_{GS} = 0V

Figure 14. DC drain current derating

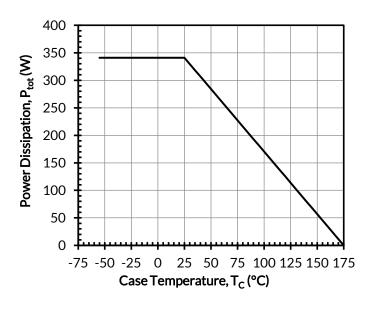


Figure 15. Total power dissipation

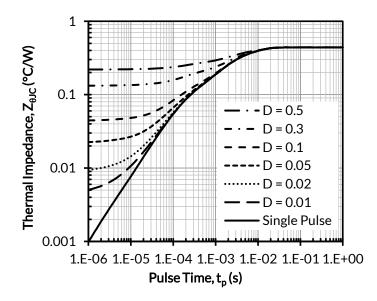


Figure 16. Maximum transient thermal impedance













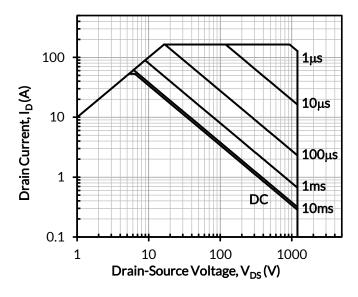


Figure 17. Safe operation area at T_C = 25°C, D = 0, Parameter t_p

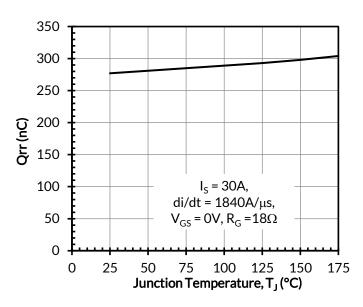


Figure 18. Reverse recovery charge Qrr vs. junction temperature at V_{DS} = 800V

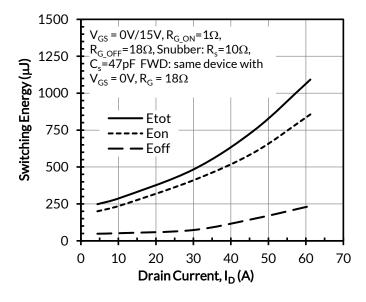


Figure 19. Clamped inductive switching energy vs. drain current at V_{DS} = 800V and T_J = 25°C

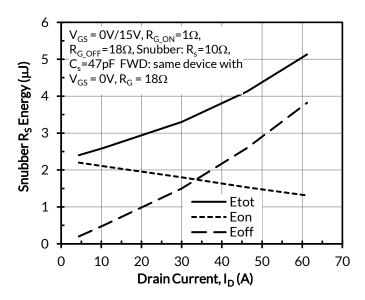


Figure 20. RC snubber energy losses vs. drain current at V_{DS} = 800V, I_{D} = 30A, and T_{J} = 25°C



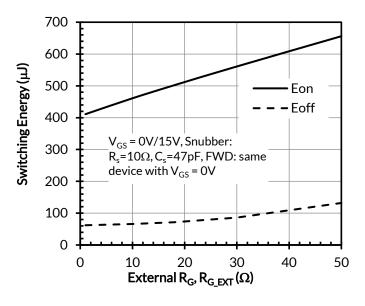








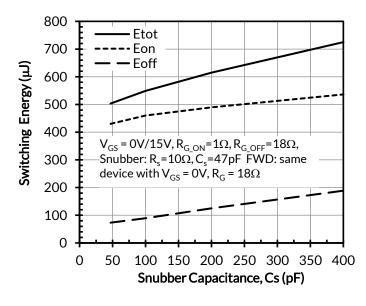




2 Eon **Eoff** Snubber Rs Energy (μJ) 1.5 1 $V_{GS} = 0V/15V$, Snubber: R_s =10 Ω , C_s =47pF: FWD: same device with $V_{GS} = 0V$ 0.5 0 10 20 30 40 50 External R_G , $R_{GEXT}(\Omega)$

Figure 21. Clamped inductive switching energies vs. $R_{G,EXT}$ at V_{DS} = 800V, I_D =30A, and T_J = 25°C

Figure 22. RC snubber energy losses vs. $R_{G,EXT}$ at V_{DS} = 800V, I_D = 30A, and T_J = 25°C



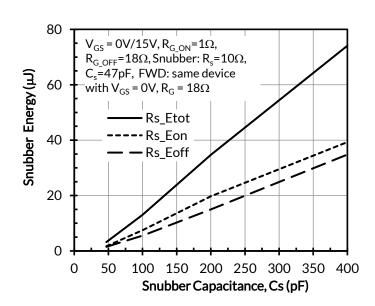


Figure 23. Clamped inductive switching energies vs. snubber capacitance C_S at V_{DS} = 800V, I_D = 30A, and

Figure 24. RC snubber energy losses vs. snubber capacitance C_S at V_{DS} = 800V, I_D = 30A, and T_J = 25°C



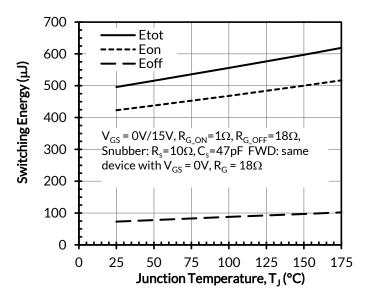












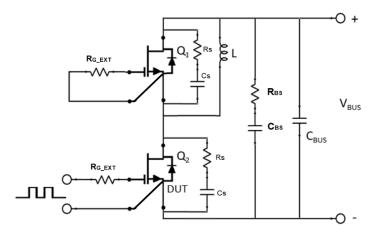


Figure 25. Clamped inductive switching energy vs. junction temperature at V_{DS} =800V and I_{D} =30A

Figure 26. Schematic of the half-bridge mode switching test circuit. Note, a bus RC snubber (R_{BS} = 2.5 Ω , C_{BS} =100nF) is used to reduce the power loop high frequency oscillations.













Applications Information

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Q_{rr}) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode. Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see www.unitedsic.com.

A snubber circuit with a small $R_{(G)}$, or gate resistor, provides better EMI suppression with higher efficiency compared to using a high $R_{(G)}$ value. There is no extra gate delay time when using the snubber circuitry, and a small $R_{(G)}$ will better control both the turn-off $V_{(DS)}$ peak spike and ringing duration, while a high $R_{(G)}$ will damp the peak spike but result in a longer delay time. In addition, the total switching loss when using a snubber circuit is less than using high $R_{(G)}$, while greatly reducing $E_{(OFF)}$ from mid-to-full load range with only a small increase in $E_{(ON)}$. Efficiency will therefore improve with higher load current. For more information on how a snubber circuit will improve overall system performance, visit the UnitedSiC website at www.unitedsic.com

Important notice

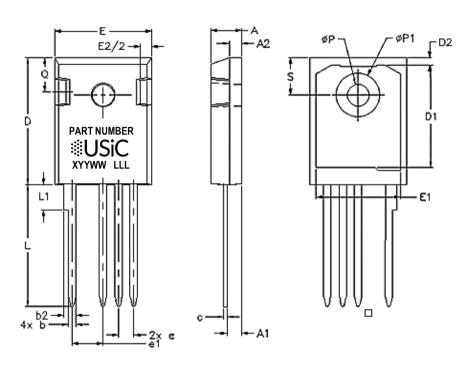
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Datasheet: UF4SC120030K4S Rev. B, January 2025 12



TO-247-4L PACKAGE OUTLINE, PART MARKING AND TUBE SPECIFICATIONS

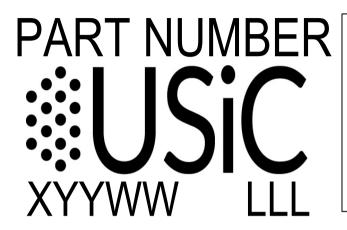
PACKAGE OUTLINE



DIM	INC	HES	MILLIMETERS		
	MIN	MAX	MIN	MAX	
Α	0.185	0.209	4.7	5.31	
A1	0.087	0.102	2.21	2.59	
A2	0.059	0.098	1.5	2.49	
b	0.039	0.055	0.99	1.4	
b2	0.065	0.094	1.65	2.39	
С	0.015	0.035	0.38	0.89	
D	0.819	0.845	20.8	21.46	
D1	0.515	-	13.08	-	
D2	0.02	0.053	0.51	1.35	
E	0.61	0.64	15.49	16.26	
е	0.100 BSC		2.54 BSC		
e1	0.19	0.21	4.83	5.33	
E1	0.53	-	13.46 -		
E2	0.14	0.16	3.56	4.06	
L	0.78	0.8	19.81	20.32	
L1	-	0.177		4.5	
ФР	0.14	0.144	3.56	3.66	
ФР1	0.278	0.291	7.06 7.39		
Q	0.212	0.244	5.38 6.2		
S	0.243 BSC		6.17 BSC		



TO-247-4L PACKAGE OUTLINE, PART MARKING AND TUBE SPECIFICATIONS



PART NUMBER = REFER TO
DS PN DECODER FOR DETAILS

X = ASSEMBLY SITE

YY = YEAR

WW = WORK WFFK

LLL = LOT ID

PACKING TYPE

ANTI-STATIC TUBE

QUANTITY /TUBE: 30 UNITS

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